

LiPON-Enabled Reduction of V_2O_5 during Fabrication of Thin-Film Ionic Devices

Leopoldo Tapia-Aracayo¹, David Murdock Stewart¹, and Gary Rubloff¹

¹A. James Clark School of Engineering, University of Maryland, College Park, Maryland 20742, United States

*ltapiaar@umd.edu

Vanadium (V) Oxide (V_2O_5) is a well-researched layered oxide with high capacity (375 mAh/g), often cited for its applications in energy storage, electrochromic, and neuromorphic applications. In the field of thin-film ionic devices, we can sputter Lithium Phosphorus Oxynitride (LiPON) on top of crystalline V_2O_5 , creating our electrolyte/electrode stack. This sequence simplifies the fabrication of thin-film ionic batteries as sputtering LiPON can insert Lithium up to 2 Li^+ per V_2O_5 . We wanted to address the roughness of the LiPON/ V_2O_5 interface by altering the fabrication steps to form a smooth interface, but unintentionally reduced the V_2O_5 to a VO_2 phase.

This smooth interface was achieved by sputtering amorphous V_2O_5 thin films in Ar/O_2 environment, then coated with LiPON, and subjected to post-deposition annealing in N_2 gas environment at 300 °C. The N_2 gas environment for the post-deposition annealing would crystallize the V_2O_5 and preserve the LiPON composition. We tracked the formation of a VO_2 phase, which was not observed for N_2 annealed V_2O_5 without LiPON, which remains VO_2 free. We used electrochemical cycling to probe the presence and evolution of the VO_2 phase, illustrating VO_2 reaction peaks instead of characteristic crystalline V_2O_5 peaks in the 2.2 V – 4.0 V vs Li^+/Li window. (Seen in Figure 1). We will discuss how this behavior may be caused by LiPON-enabled reduction pathways at the buried interface. We confirm this reduction is limited to the interface as analysis via Raman identifies lithiated V_2O_5 phases. Systematic variation of LiPON sputtering parameters and annealing conditions, while holding LiPON thickness constant, reveal processing regimes that drive VO_2 formation versus preserving V_2O_5 . Ultimately, preserving the morphological benefits of a smooth LiPON/ V_2O_5 interface while constraining VO_2 formation, providing guidance for designing desired application-specific vanadium-oxide phases.

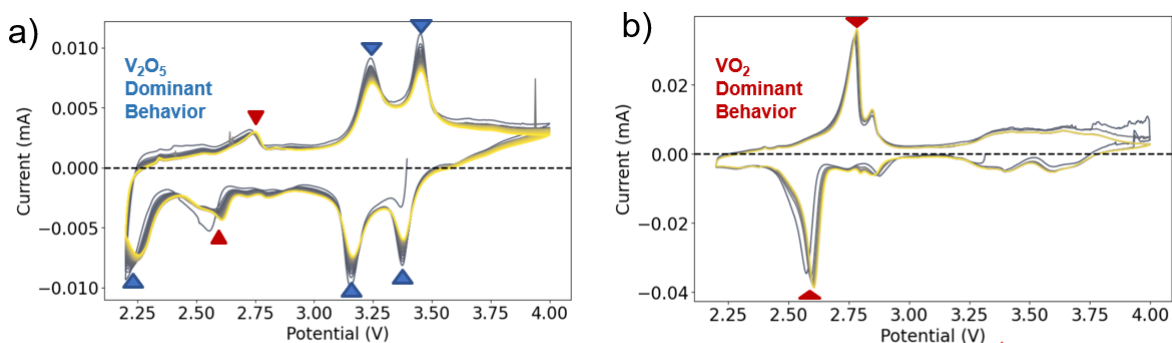


Figure 1): Left Figure illustrates V_2O_5 electrochemical peaks (blue arrows) with two emerging VO_2 peaks (red arrows) at 2.6V and 2.75V. Right Figure highlights VO_2 Dominant Electrochemical behavior, where the two main peaks from the left are the primarily Lithium insertion and extraction peaks for VO_2 . Both figures contain the same LiPON/ V_2O_5 stack.